

Sulfuric Acid 96%  
CMOS



Material No.: 9684-03  
Batch No.: 0000117595  
Manufactured Date: 2015/07/21  
Retest Date: 2020/07/19

## Certificate of Analysis

| Test                                    | Specification | Result |
|---|---------------|--------|
| Assay (H <sub>2</sub> SO <sub>4</sub> ) | 95.0 – 97.0 % | 96.1   |
| Color (APHA)                            | <= 10         | 5      |
| Residue after Ignition                  | <= 2 ppm      | < 1    |
| Chloride (Cl)                           | <= 0.1 ppm    | < 0.1  |
| Nitrate (NO <sub>3</sub> )              | <= 0.2 ppm    | < 0.1  |
| Phosphate (PO <sub>4</sub> )            | <= 0.3 ppm    | < 0.1  |
| Trace Impurities – Aluminum (Al)        | <= 50.0 ppb   | < 5.0  |
| Arsenic and Antimony (as As)            | <= 5 ppb      | < 2    |
| Trace Impurities – Barium (Ba)          | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Beryllium (Be)       | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Bismuth (Bi)         | <= 20.0 ppb   | < 10.0 |
| Trace Impurities – Boron (B)            | <= 10.0 ppb   | < 5.0  |
| Trace Impurities – Cadmium (Cd)         | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Calcium (Ca)         | <= 50.0 ppb   | 5.2    |
| Trace Impurities – Chromium (Cr)        | <= 50.0 ppb   | < 1.0  |
| Trace Impurities – Cobalt (Co)          | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Copper (Cu)          | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Gallium (Ga)         | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Germanium (Ge)       | <= 10.0 ppb   | < 10.0 |
| Trace Impurities – Gold (Au)            | <= 20.0 ppb   | < 5.0  |
| Heavy Metals (as Pb)                    | <= 200 ppb    | < 100  |
| Trace Impurities – Iron (Fe)            | <= 100.0 ppb  | 1.1    |
| Trace Impurities – Lead (Pb)            | <= 20.0 ppb   | < 1.0  |
| Trace Impurities – Lithium (Li)         | <= 10.0 ppb   | < 1.0  |

| Test                                | Specification | Result |
|-------------------------------------|---------------|--------|
| Trace Impurities – Magnesium (Mg)   | <= 50.0 ppb   | < 1.0  |
| Trace Impurities – Manganese (Mn)   | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Mercury (Hg)     | <= 5.0 ppb    | < 0.1  |
| Trace Impurities – Molybdenum (Mo)  | <= 10.0 ppb   | < 5.0  |
| Trace Impurities – Nickel (Ni)      | <= 10.0 ppb   | < 5.0  |
| Trace Impurities – Niobium (Nb)     | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Potassium (K)    | <= 50.0 ppb   | < 10.0 |
| Trace Impurities – Silicon (Si)     | <= 50.0 ppb   | < 10.0 |
| Trace Impurities – Silver (Ag)      | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Sodium (Na)      | <= 100.0 ppb  | 13.1   |
| Trace Impurities – Strontium (Sr)   | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Tantalum (Ta)    | <= 10.0 ppb   | < 5.0  |
| Trace Impurities – Thallium (Tl)    | <= 20.0 ppb   | < 5.0  |
| Trace Impurities – Tin (Sn)         | <= 50.0 ppb   | < 10.0 |
| Trace Impurities – Titanium (Ti)    | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Vanadium (V)     | <= 10.0 ppb   | < 1.0  |
| Trace Impurities – Zinc (Zn)        | <= 50.0 ppb   | < 1.0  |
| Trace Impurities – Zirconium (Zr)   | <= 10.0 ppb   | < 1.0  |
| Particle Count – 0.5 µm and greater | <= 60 par/ml  | 19     |
| Particle Count – 1.0 µm and greater | <= 10 par/ml  | 4      |

For Microelectronic Use

Storage Conditions: Recommended Storage Conditions: 15° – 100°F  
Country of Origin: US  
Packaging Site: Phillipsburg Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004, FSSC 22000  
 Paris, KY 9001:2008  
 Mexico City, Mexico 9001:2008  
 Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003  
 Gliwice, Poland 9001:2008  
 Selangor, Malaysia 9001:2008  
 Dehradun, India, 9001:2008, 14001:2004, 13485:2003  
 Mumbai, India, 9001:2008, 17025:2005  
 Panoli, India 9001:2008



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